

STGW60H65F STGWT60H65F

60 A, 650 V field stop trench gate IGBT

Datasheet - production data

Features

- High speed switching
- Tight parameter distribution
- Safe paralleling
- Low thermal resistance
- 6 µs short-circuit withstand time
- Lead free package

Applications

- Photovoltaic inverters
- Uninterruptible power supply
- Welding
- Power factor correction
- High switching frequency converters



Using advanced proprietary trench gate and field stop structure, this IGBT leads to an optimized compromise between conduction and switching losses maximizing the efficiency for high switching frequency converters. Furthermore, a slightly positive $V_{\text{CE(sat)}}$ temperature coefficient and a very tight parameter distribution result in an easier paralleling operation.

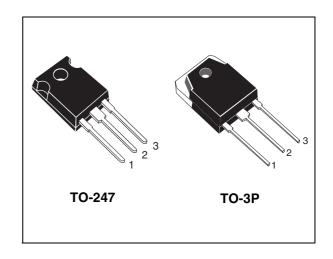


Figure 1. Internal schematic diagram

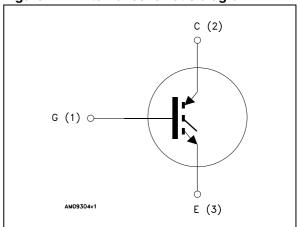


Table 1. Device summary

Order code	Marking	Package	Packaging
STGW60H65F	GW60H65F	TO-247	Tube
STGWT60H65F	G60H65F	TO-3P	Tube

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{CES}	Collector-emitter voltage (V _{GE} = 0)	650	V
I _C	Continuous collector current at $T_C = 25$ °C	120	Α
I _C	Continuous collector current at T _C = 100 °C	60	Α
I _{CP} ⁽¹⁾	Pulsed collector current	240	Α
V _{GE}	Gate-emitter voltage	± 20	٧
P _{TOT}	Total dissipation at T _C = 25 °C	360	W
t _{SC}	Short-circuit withstand time at $V_{CC} = 400 \text{ V}$, $V_{GE} = 15 \text{ V}$	6	μs
T _{STG}	Storage temperature range - 55 to 150		°C
T _J	Operating junction temperature	- 55 to 150	

^{1.} Pulse width limited by maximum junction temperature and turn-off within RBSOA

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thJC}	Thermal resistance junction-case	0.35	°C/W
R _{thJA}	Thermal resistance junction-ambient	50	°C/W

2 Electrical characteristics

 $T_J = 25$ °C unless otherwise specified.

Table 4. Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)CES}	Collector-emitter breakdown voltage (V _{GE} = 0)	I _C = 2 mA	650			V
	Collector-emitter saturation	$V_{GE} = 15 \text{ V}, I_{C} = 60 \text{ A}$		1.9		
V _{CE(sat)}	voltage	$V_{GE} = 15 \text{ V}, I_{C} = 60 \text{ A}$ $T_{J} = 125 \text{ °C}$		2.1		V
V _{GE(th)}	Gate threshold voltage	$V_{CE} = V_{GE}$, $I_C = 1 \text{ mA}$		6.0		V
I _{CES}	Collector cut-off current (V _{GE} = 0)	V _{CE} = 650 V			25	μΑ
I _{GES}	Gate-emitter leakage current (V _{CE} = 0)	V _{GE} = ± 20 V			250	nA

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{ies} C _{oes} C _{res}	Input capacitance Output capacitance Reverse transfer capacitance	V _{CE} = 25 V, f = 1 MHz, V _{GE} =0	-	7150 275 140	-	pF pF pF
Qg	Total gate charge			217		nC
Q _{ge}	Gate-emitter charge	$V_{CC} = 400 \text{ V, } I_{C} = 60 \text{ A,}$ $V_{GE} = 15 \text{ V}$		67		nC
Q _{gc}	Gate-collector charge	GL -		97		nC

Table 6. Switching on/off (inductive load)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} (1) t _r (1) (di/dt) _{on} (1)	Turn-on delay time Current rise time Turn-on current slope	$V_{CE} = 400 \text{ V}, I_{C} = 60 \text{ A},$ $R_{G} = 10 \Omega, V_{GE} = 15 \text{ V}$	-	65 30 2000	-	ns ns A/µs
$t_{d(on)}^{(1)}$ $t_r^{(1)}$ $(di/dt)_{on}^{(1)}$	Turn-on delay time Current rise time Turn-on current slope	$V_{CE} = 400 \text{ V}, I_{C} = 60 \text{ A},$ $R_{G} = 10 \Omega, V_{GE} = 15 \text{ V}$ $T_{J} = 125 \text{ °C}$	-	63 33 1800	-	ns ns A/µs
$\begin{array}{c} t_{r}(V_{off}) \\ t_{d}(_{off}) \\ t_{f} \end{array}$	Off voltage rise time Turn-off delay time Current fall time	$V_{CE} = 400 \text{ V}, I_{C} = 60 \text{ A},$ $R_{G} = 10 \Omega, V_{GE} = 15 \text{ V}$	1	35 180 43	-	ns ns ns
$t_{r}(V_{off})$ $t_{d}(_{off})$ t_{f}	Off voltage rise time Turn-off delay time Current fall time	$V_{CE} = 400 \text{ V}, I_{C} = 60 \text{ A},$ $R_{G} = 10 \Omega, V_{GE} = 15 \text{ V}$ $T_{J} = 125 \text{ °C}$	-	46 210 85	-	ns ns ns

Eon is the turn-on losses when a SiC diode (STPSC1206D) is used in the test circuit in Figure 17. If the IGBT is offered in a package with a co-pack diode, the co-pack diode is used as external diode. IGBTs and diode are at the same temperature (25 °C and 125 °C).

Table 7. Switching energy (inductive load)

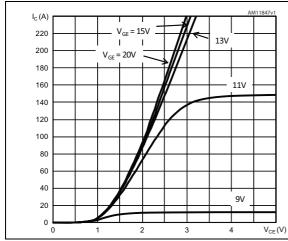
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Eon (1)	Turn-on switching losses	$V_{CF} = 400 \text{ V}, I_{C} = 60 \text{ A},$		0.75		mJ
E _{off} ⁽²⁾	Turn-off switching losses	$R_G = 10 \Omega$, $V_{GF} = 15 V$	-	1.05	-	mJ
E _{ts}	Total switching losses			1.80		mJ
Eon (1)	Turn-on switching losses	$V_{CE} = 400 \text{ V}, I_{C} = 60 \text{ A},$		0.8		mJ
E _{off} (2)	Turn-off switching losses	$R_G = 10 \Omega$, $V_{GE} = 15 V$	-	1.4	-	mJ
E _{ts}	Total switching losses	T _J = 125 °C		2.2		mJ

Eon is the turn-on losses when a SiC diode (STPSC1206D) is used in the test circuit in *Figure 17*. If the IGBT is offered in a package with a co-pack diode, the co-pack diode is used as external diode. IGBTs and diode are at the same temperature (25 °C and 125 °C).

^{2.} Turn-off losses include also the tail of the collector current.

2.1 Electrical characteristics (curves)

Figure 2. Output characteristics ($T_J = -40 \,^{\circ}\text{C}$) Figure 3. Output characteristics ($T_J = 25 \,^{\circ}\text{C}$)



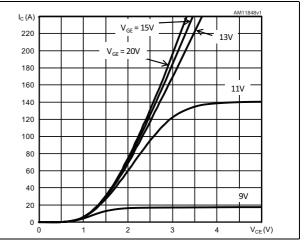
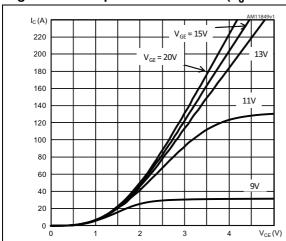


Figure 4. Output characteristics ($T_J = 150$ °C) Figure 5. Transfer characteristics



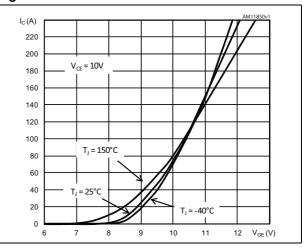


Figure 6. V_{CE(SAT)} vs. junction temperature

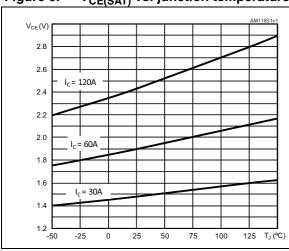
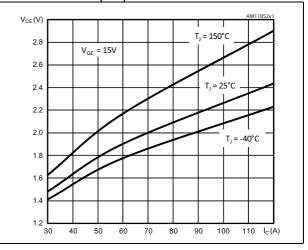


Figure 7. $V_{CE(SAT)}$ vs. collector current



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Figure 8. Normalized $V_{GE(th)}$ vs. junction temperature

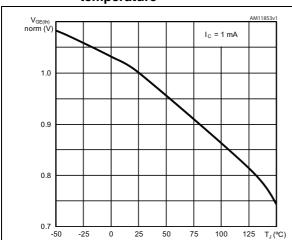


Figure 9. Gate charge vs. gate-emitter voltage

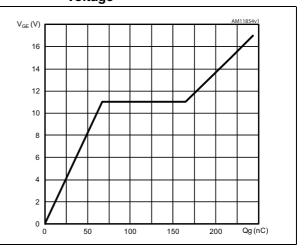


Figure 10. Capacitance variations (f = 1 MHz, $V_{GE} = 0$)

Figure 11. Switching losses vs. collector current

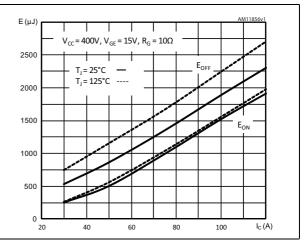
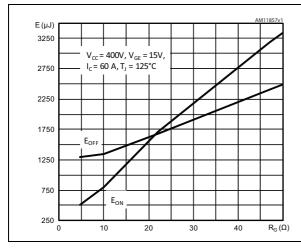


Figure 12. Switching losses vs. gate resistance

Figure 13. Switching losses vs. temperature



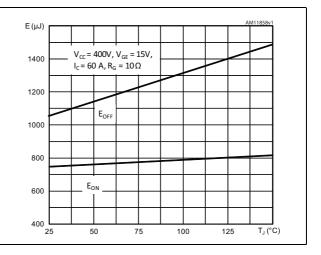


Figure 14. Turn-OFF SOA

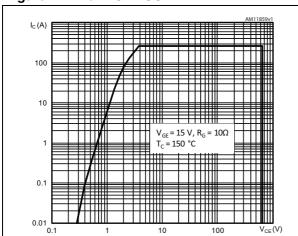


Figure 15. Short circuit time & current vs. V_{GE}

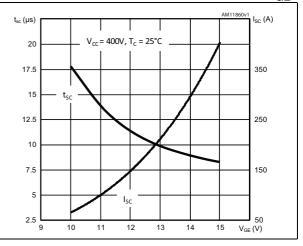
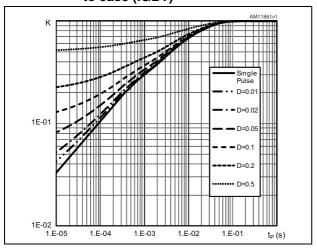


Figure 16. Maximum normalized Z_{th} junction to case (IGBT)



3 Test circuits

Figure 17. Test circuit for inductive load switching

Figure 18. Gate charge test circuit

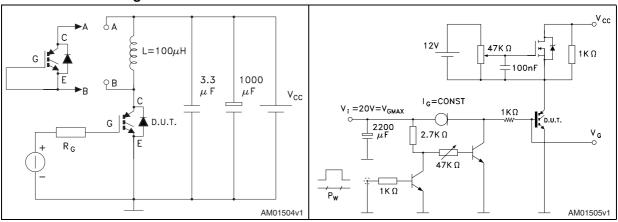
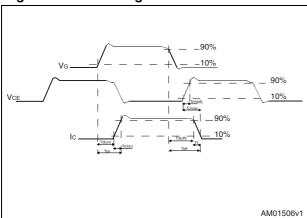


Figure 19. Switching waveform



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4 Package mechanical data

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Table 8. TO-247 mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
E	15.45		15.75
е		5.45	
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S		5.50	

Figure 20. TO-247 drawing

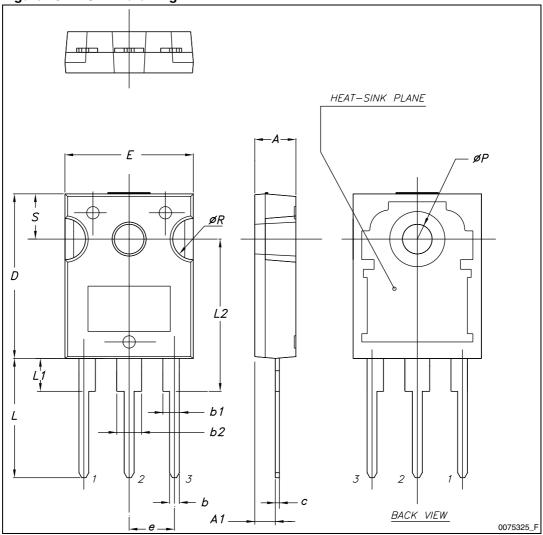
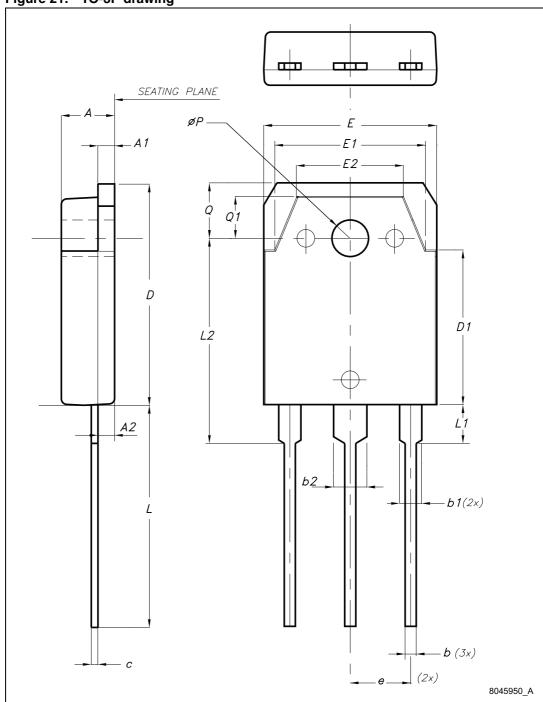


Table 9. TO-3P mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
Α	4.60		5
A1	1.45	1.50	1.65
A2	1.20	1.40	1.60
b	0.80	1	1.20
b1	1.80		2.20
b2	2.80		3.20
С	0.55	0.60	0.75
D	19.70	19.90	20.10
D1		13.90	
Е	15.40		15.80
E1		13.60	
E2		9.60	
е	5.15	5.45	5.75
L	19.50	20	20.50
L1		3.50	
L2	18.20	18.40	18.60
øΡ	3.10		3.30
Q		5	
Q1		3.80	

Figure 21. TO-3P drawing



5 Revision history

Table 10. Document revision history

Date Revision Changes		Changes
05-Jul-2011	1	Initial release.
12-Jan-2012	2	Document status promoted from preliminary data to datasheet.
10-Feb-2012	3	Added: Section 2.1: Electrical characteristics (curves).
31-Jul-2012	4	Updated: Figure 8 on page 6.
09-Jan-2013	5	Added: new order code STGWT60H65F, package mechanical data Table 9 on page 11 and Figure 21 on page 12.

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